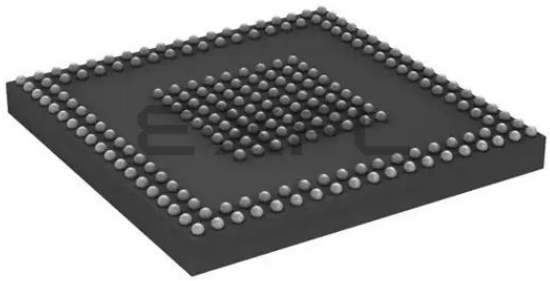

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	XCore
Core Size	32-Bit 12-Core
Speed	1000MIPS
Connectivity	Configurable
Peripherals	-
Number of I/O	73
Program Memory Size	128KB (32K x 32)
Program Memory Type	SRAM
EEPROM Size	-
RAM Size	-
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 8x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	217-LFBGA
Supplier Device Package	217-FBGA (16x16)
Purchase URL	https://www.e-xfl.com/product-detail/xmos/xs1-u12a-128-fb217-i10

Table of Contents

1 xCORE Multicore Microcontrollers

The XS1-U Series is a comprehensive range of 32-bit multicore microcontrollers that brings the low latency and timing determinism of the xCORE architecture to mainstream embedded applications. Unlike conventional microcontrollers, xCORE multicore microcontrollers execute multiple real-time tasks simultaneously and communicate between tasks using a high speed network. Because xCORE multicore microcontrollers are completely deterministic, you can write software to implement functions that traditionally require dedicated hardware.

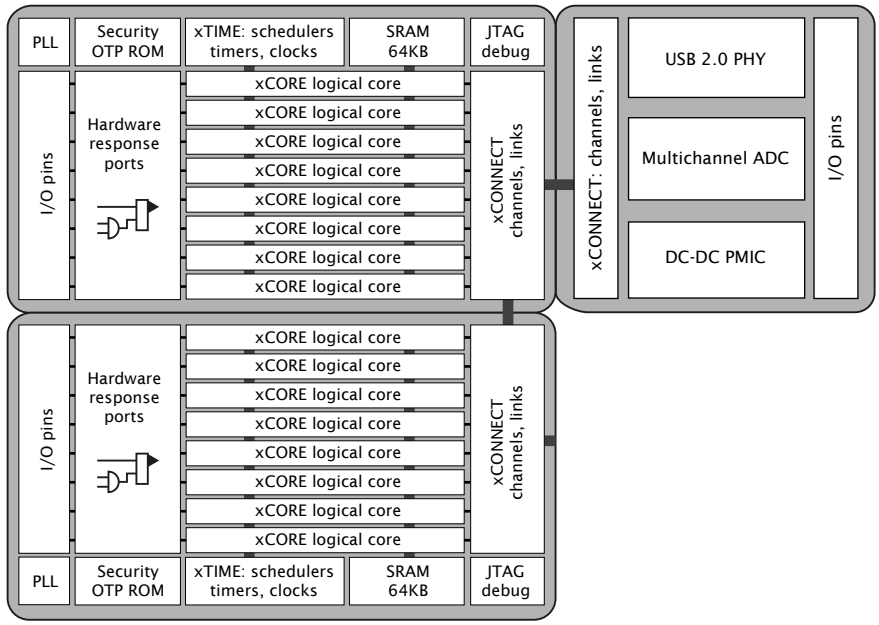


Figure 1: XS1-U Series: 6-16 core devices

Key features of the XS1-U12A-128-FB217 include:

- **Tiles**: Devices consist of one or more xCORE tiles. Each tile contains between four and eight 32-bit xCOREs with highly integrated I/O and on-chip memory.
- **Logical cores** Each logical core can execute tasks such as computational code, DSP code, control software (including logic decisions and executing a state machine) or software that handles I/O. Section 7.1
- **xTIME scheduler** The xTIME scheduler performs functions similar to an RTOS, in hardware. It services and synchronizes events in a core, so there is no requirement for interrupt handler routines. The xTIME scheduler triggers cores on events generated by hardware resources such as the I/O pins, communication channels and timers. Once triggered, a core runs independently and concurrently to other cores, until it pauses to wait for more events. Section 7.2

Signal	Function		Type	Properties
X1D51	XLC^{2}_{out}	$32A^{2}$	I/O	PD_S
X1D52	XLC^{1}_{out}	$32A^{3}$	I/O	PD_S
X1D53	XLC^{0}_{out}	$32A^{4}$	I/O	PD_S
X1D54	XLC^{0}_{in}	$32A^{5}$	I/O	PD_S
X1D55	XLC^{1}_{in}	$32A^{6}$	I/O	PD_S
X1D56	XLC^{2}_{in}	$32A^{7}$	I/O	PD_S
X1D57	XLC^{3}_{in}	$32A^{8}$	I/O	PD_S
X1D58	XLC^{4}_{in}	$32A^{9}$	I/O	PD_S
X1D61	XLD^{4}_{out}	$32A^{10}$	I/O	PD_S
X1D62	XLD^{3}_{out}	$32A^{11}$	I/O	PD_S
X1D63	XLD^{2}_{out}	$32A^{12}$	I/O	PD_S
X1D64	XLD^{1}_{out}	$32A^{13}$	I/O	PD_S
X1D65	XLD^{0}_{out}	$32A^{14}$	I/O	PD_S
X1D66	XLD^{0}_{in}	$32A^{15}$	I/O	PD_S
X1D67	XLD^{1}_{in}	$32A^{16}$	I/O	PD_S
X1D68	XLD^{2}_{in}	$32A^{17}$	I/O	PD_S
X1D69	XLD^{3}_{in}	$32A^{18}$	I/O	PD_S
X1D70	XLD^{4}_{in}	$32A^{19}$	I/O	PD_S

If a different tile frequency is required (eg, 500 MHz), then the PLL must be reprogrammed after boot to provide the required tile frequency. The XMOS tools perform this operation by default. Further details on configuring the clock can be found in the XS1-L Clock Frequency Control document, X1433.

9 Boot Procedure

The device is kept in reset by driving RST_N low. When in reset, all GPIO pins are high impedance. When the device is taken out of reset by releasing RST_N the processor starts its internal reset process. After approximately 750,000 input clocks, all GPIO pins have their internal pull-resistor enabled, and the processor boots at a clock speed that depends on MODE0 and MODE1.

The processor boot procedure is illustrated in Figure 9. In normal usage, MODE[4:2] controls the boot source according to the table in Figure 10. If bit 5 of the security register (*see* §10.1) is set, the device boots from OTP.

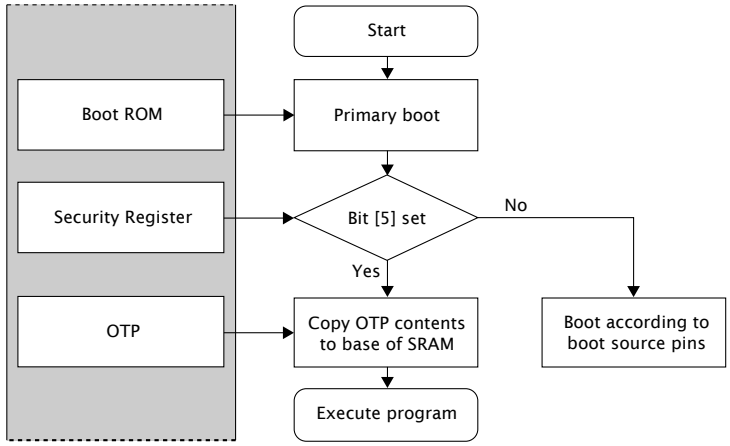


Figure 9: Boot procedure

MODE [4]	MODE [3]	MODE [2]	Boot Source
X	0	0	None: Device waits to be booted via JTAG
X	0	1	Reserved
0	1	0	Tile0 boots from link B, Tile1 from channel end 0 via Tile0
0	1	1	Tile0 boots from SPI, Tile1 from channel end 0 via Tile0
1	1	0	Tile0 and Tile1 independently enable link B and internal links (E, F, G, H), and boot from channel end 0
1	1	1	Tile0 and Tile 1 boot from SPI independently

Figure 10: Boot source pins

The boot image has the following format:

- A 32-bit program size s in words.

2. Input a word on channel-end 0. It will use this word as a channel to acknowledge the boot. Provide the null-channel-end 0x0000FF02 if no acknowledgment is required.
3. Input the boot image specified above, including the CRC.
4. Input an END control token.
5. Output an END control token to the channel-end received in step 2.
6. Free channel-end 0.
7. Jump to the loaded code.

9.3 Boot from OTP

If an xCORE tile is set to use secure boot (see Figure 9), the boot image is read from address 0 of the OTP memory in the tile's security module.

This feature can be used to implement a secure bootloader which loads an encrypted image from external flash, decrypts and CRC checks it with the processor, and discontinues the boot process if the decryption or CRC check fails. XMOS provides a default secure bootloader that can be written to the OTP along with secret decryption keys.

Each tile has its own individual OTP memory, and hence some tiles can be booted from OTP while others are booted from SPI or the channel interface. This enables systems to be partially programmed, dedicating one or more tiles to perform a particular function, leaving the other tiles user-programmable.

9.4 Security register

The security register enables security features on the xCORE tile. The features shown in Figure 12 provide a strong level of protection and are sufficient for providing strong IP security.

10 Memory

10.1 OTP

Each xCORE Tile integrates 8 KB one-time programmable (OTP) memory along with a security register that configures system wide security features. The OTP holds data in four sectors each containing 512 rows of 32 bits which can be used to implement secure bootloaders and store encryption keys. Data for the security register is loaded from the OTP on power up. All additional data in OTP is copied from the OTP to SRAM and executed first on the processor.

The OTP memory is programmed using three special I/O ports: the OTP address port is a 16-bit port with resource ID 0x100200, the OTP data is written via a 32-bit

to save power (see Appendix I). To ensure that the real-time counter increases linearly over time, a programmable value is added to the counter on every 31,250 Hz clock-tick. This means that the clock will run at a granularity of 31,250 Hz but still maintain real-time in terms of the frequency of the main oscillator. If an accurate clock is required, even whilst asleep, then an external crystal or oscillator shall be provided that is used in both AWAKE and ASLEEP state.

The designer has to make a trade-off between accuracy of clocks when asleep and awake, costs, and deep-sleep power consumption. Four example designs are shown in Figure 15.

Figure 15: Example trade-offs in oscillator selection

Clocks used		Power	BOM	Accuracy	
Awake	Asleep	Asleep	costs	Awake	Asleep
20 Mhz SiOsc	31,250 SiOsc	lowest	lowest	lowest	lowest
24 MHz Crystal	31,250 SiOsc	lowest	medium	highest	lowest
5 MHz ext osc	5 MHz ext osc	medium	highest	highest	highest
24 MHz Crystal	24 MHz crystal	highest	medium	highest	highest

During deep-sleep, the program can store some state in 128 bytes of Deep Sleep Memory.

14.4 Requirements during sleep mode

Whilst in sleep mode, the device must still be powered as normal over 3V3 or 5V0 on VSUP, and 3V3 on VDDIO; however it will draw less power on both VSUP and VDDIO.

For best results (lowest power):

- The XTAL bias and XTAL oscillators should be switched off.
- The sleep register should be configured to
  - Disable all power supplies except DCDC2.
  - Set all power supplies to PFM mode
  - Mask the clock
  - Assert reset
- All GPIO and JTAG pins should be quiescent, and none should be driven against a pull-up or pull-down.
- 3V3 should be supplied as the input voltage to VSUP.

This will result in a power consumption of less than 100 uA on both VSUP and VDDIO.

If any power supply loses power-good status during the asleep-to-awake or awake-to-asleep transitions, a system reset is issued.

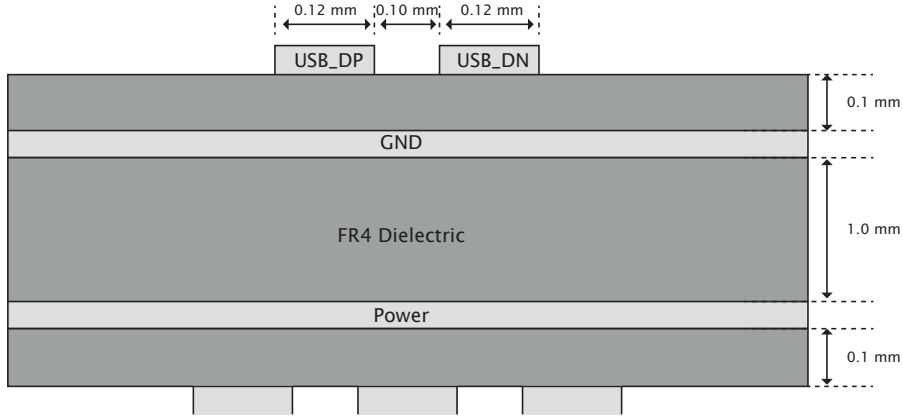


Figure 21: Example USB board stack

For best results, most of the routing should be done on the top layer (assuming the USB connector and XS1-U12A-128-FB217 are on the top layer) closest to GND. Reference planes should be below the transmission lines in order to maintain control of the trace impedance.

We recommend that the high-speed clock and high-speed USB differential pairs are routed first before any other routing. When routing high speed USB signals, the following guidelines should be followed:

- High speed differential pairs should be routed together.
- High-speed USB signal pair traces should be trace-length matched. Maximum trace-length mismatch should be no greater than 4mm.
- Ensure that high speed signals (clocks, USB differential pairs) are routed as far away from off-board connectors as possible.
- High-speed clock and periodic signal traces that run parallel should be at least 1.27mm away from USB_DP/USB_DN (see Figure 20).
- Low-speed and non-periodic signal traces that run parallel should be at least 0.5mm away from USB_DP/USB_DN (see Figure 20).
- Route high speed USB signals on the top of the PCB wherever possible.
- Route high speed USB traces over continuous power planes, with no breaks. If a trade-off must be made, changing signal layers is preferable to crossing plane splits.
- Follow the $20 \times h$ rule; keep traces $20 \times h$ (the height above the power plane) away from the edge of the power plane.
- Use a minimum of vias in high speed USB traces.

- Avoid corners in the trace. Where necessary, rather than turning through a 90 degree angle, use two 45 degree turns or an arc.
- DO NOT route USB traces near clock sources, clocked circuits or magnetic devices.
- Avoid stubs on high speed USB signals.

16.3 Land patterns and solder stencils

The land pattern recommendations in this document are based on a RoHS compliant process and derived, where possible, from the nominal *Generic Requirements for Surface Mount Design and Land Pattern Standards* IPC-7351B specifications. This standard aims to achieve desired targets of heel, toe and side fillets for solder-joints.

Solder paste and ground via recommendations are based on our engineering and development kit board production. They have been found to work and optimized as appropriate to achieve a high yield. These factors should be taken into account during design and manufacturing of the PCB.

The following land patterns and solder paste contains recommendations. Final land pattern and solder paste decisions are the responsibility of the customer. These should be tuned during manufacture to suit the manufacturing process.

The package is a 217 pin Fine Ball Grid Array package on a 0.8mm pitch with 0.4mm balls.

An example land pattern is shown in Figure 22.

Pad widths and spacings are such that solder mask can still be applied between the pads using standard design rules. This is highly recommended to reduce solder shorts.

16.4 Ground and Thermal Vias

Vias next to every other ground ball into the ground plane of the PCB are recommended for a low inductance ground connection and good thermal performance. Vias with with a 0.6mm diameter annular ring and a 0.3mm drill would be suitable.

16.5 Moisture Sensitivity

XMOS devices are, like all semiconductor devices, susceptible to moisture absorption. When removed from the sealed packaging, the devices slowly absorb moisture from the surrounding environment. If the level of moisture present in the device is too high during reflow, damage can occur due to the increased internal vapour pressure of moisture. Example damage can include bond wire damage, die lifting, internal or external package cracks and/or delamination.

All XMOS devices are Moisture Sensitivity Level (MSL) 3 - devices have a shelf life of 168 hours between removal from the packaging and reflow, provided they

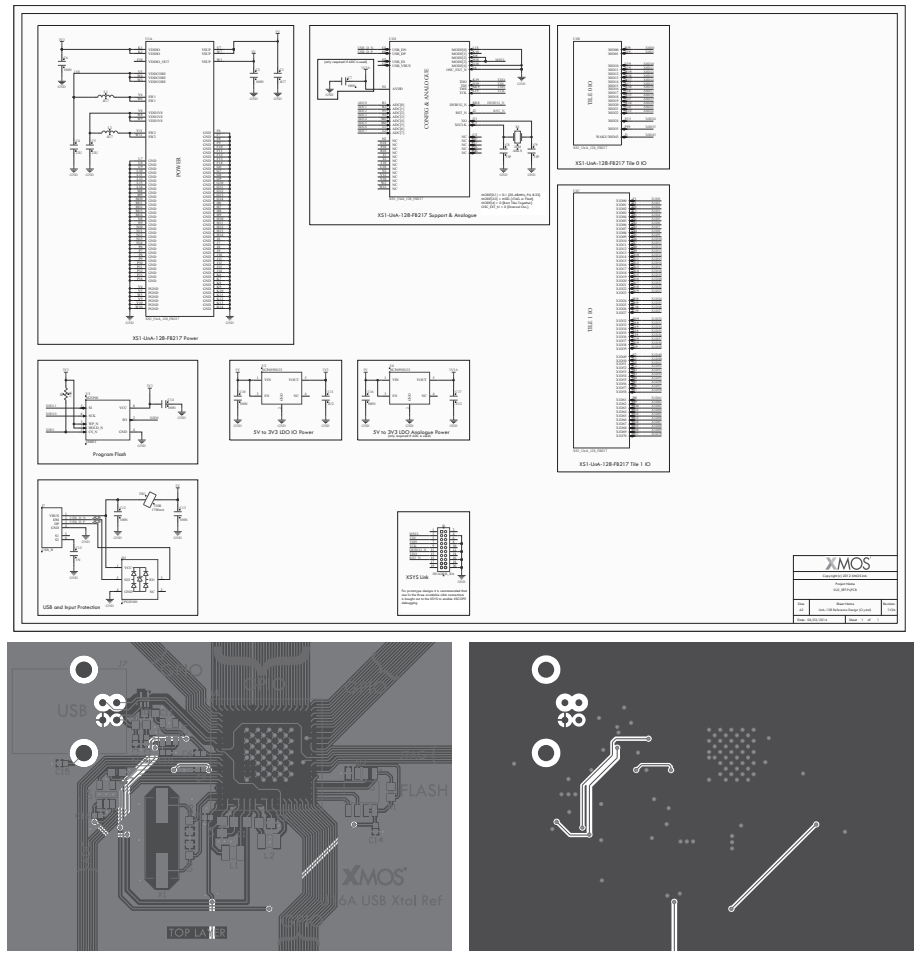


Figure 23: Example XTAL schematic, with top and bottom layout of a 2-layer PCB

18.3 DC2 Characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
VDD1V8	1V8 Supply Voltage		1.80		V	
V(RIPPLE)	Ripple Voltage (peak to peak)		10	40	mV	
V(ACC)	Voltage Accuracy	-5		5	%	A
F(S)	Switching Frequency		1		MHz	
F(SVAR)	Variation in Switching Frequency	-10		10	%	
Effic	Efficiency		80		%	
PGT(HIGH)	Powergood Threshold (High)		95		%/VDD1V8	
PGT(LOW)	Powergood Threshold (Low)		80		%/VDD1V8	

Figure 28: DC2 characteristics

A If supplied externally.

18.4 ADC Characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
N	Resolution		12		bits	
Fs	Conversion Speed			1	MSPS	
Nch	Number of Channels		8			
Vin	Input Range	0		AVDD	V	
DNL	Differential Non Linearity	-1		1.5	LSB	
INL	Integral Non Linearity	-4		4	LSB	
E(GAIN)	Gain Error	-10		10	LSB	
E(OFFSET)	Offset Error	-3		3	mV	
T(PWRUP)	Power time for ADC Clock Fclk			7	1/Fclk	
ENOB	Effective Number of bits		10			

Figure 29: ADC characteristics

18.5 USB Characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
VBUS	Power supply	0	5	5.25	V	A
ID	Device ID (OTG)	0		3.3	V	
DP	Data positive	0		3.3	V	
DN	Data negative (inverted)	0		3.3	V	

Figure 30: USB characteristics

A The VBUS pin is used for measuring the VBUS voltage only.

Contact XMOS for further details on USB characteristics.

18.6 Digital I/O Characteristics

Figure 31: Digital I/O characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
V(IH)	Input high voltage	2.00		3.60	V	A
V(IL)	Input low voltage	-0.30		0.70	V	A
V(OH)	Output high voltage	2.00			V	B, C
V(OL)	Output low voltage			0.60	V	B, C
R(PU)	Pull-up resistance		35K		Ω	D
R(PD)	Pull-down resistance		35K		Ω	D

A All pins except power supply pins.

B Ports 1A, 1D, 1E, 1H, 1I, 1J, 1K and 1L are nominal 8 mA drivers, the remainder of the general-purpose I/Os are 4 mA.

C Measured with 4 mA drivers sourcing 4 mA, 8 mA drivers sourcing 8 mA.

D Used to guarantee logic state for an I/O when high impedance. The internal pull-ups/pull-downs should not be used to pull external circuitry.

18.7 ESD Stress Voltage

Figure 32: ESD stress voltage

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
HBM	Human body model			2.00	kV	
CDM	Charged Device Model			500	V	

18.8 Device Timing Characteristics

Figure 33: Device timing characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
T(RST)	Reset pulse width	5			µs	
T(INIT)	Initialisation (On Silicon Oscillator)			TBC	ms	A
	Initialisation (Crystal Oscillator)			TBC	ms	
T(WAKE)	Wake up time (Sleep to Active)			TBC	ms	
T(SLEEP)	Sleep Time (Active to Sleep)			TBC	ms	

A Shows the time taken to start booting after RST_N has gone high.

18.9 Crystal Oscillator Characteristics

Figure 34: Crystal oscillator characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
F(FO)	Input Frequency	5		30	MHz	A

A For use with USB, the design should use a 12 or 24 MHz +/- 150 ppm crystal.

18.10 External Oscillator Characteristics

Figure 35: External oscillator characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
F(EXT)	External Frequency			100	MHz	A
V(IH)	Input high voltage	1.62		1.98	V	
V(IL)	Input low voltage			0.4	V	

A For use with USB, the design should use a 12 or 24 MHz +/- 150 ppm crystal.

18.11 Power Consumption

Figure 36: xCORE Tile currents

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
P(AWAKE)	Active Power for awake states	TBC	600	TBC	mW	
P(SLEEP)	Power when asleep	TBC	500	TBC	µW	

18.12 Clock

Figure 37: Clock

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
f(MAX)	Processor clock frequency			500	MHz	A

A Assumes typical tile and I/O voltages with nominal activity.

18.13 Processor I/O AC Characteristics

Figure 38: I/O AC characteristics

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
T(XOVALID)	Input data valid window	8			ns	
T(XOINVALID)	Output data invalid window	9			ns	
T(XIFMAX)	Rate at which data can be sampled with respect to an external clock			60	MHz	

The input valid window parameter relates to the capability of the device to capture data input to the chip with respect to an external clock source. It is calculated as the sum of the input setup time and input hold time with respect to the external clock as measured at the pins. The output invalid window specifies the time for which an output is invalid with respect to the external clock. Note that these parameters are specified as a window rather than absolute numbers since the device provides functionality to delay the incoming clock with respect to the incoming data.

Information on interfacing to high-speed synchronous interfaces can be found in the XS1 Port I/O Timing document, X5821.

18.14 xConnect Link Performance

Figure 39: Link performance

Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
B(2blinkP)	2b link bandwidth (packetized)			103	MBit/s	A, B
B(5blinkP)	5b link bandwidth (packetized)			271	MBit/s	A, B
B(2blinkS)	2b link bandwidth (streaming)			125	MBit/s	B
B(5blinkS)	5b link bandwidth (streaming)			313	MBit/s	B

A Assumes 32-byte packet in 3-byte header mode. Actual performance depends on size of the header and payload.

B 7.5 ns symbol time.

The asynchronous nature of links means that the relative phasing of CLK clocks is not important in a multi-clock system, providing each meets the required stability criteria.

18.15 JTAG Timing

Figure 40: JTAG timing

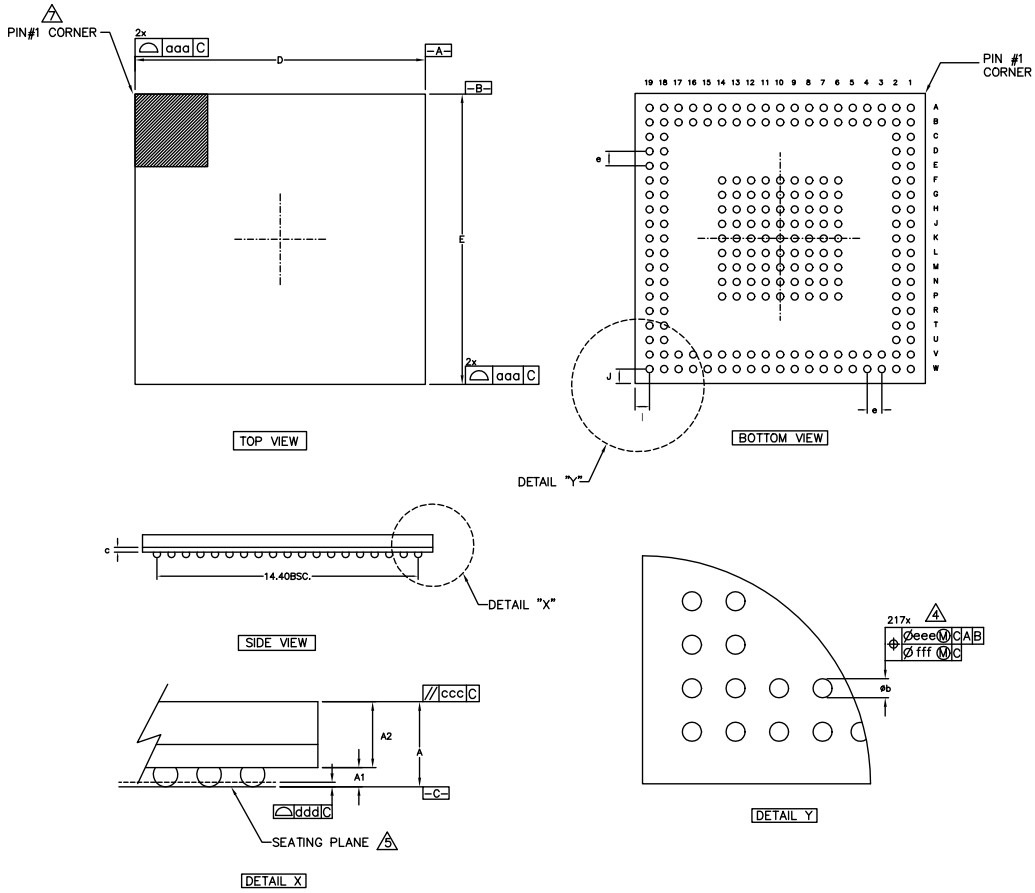
Symbol	Parameter	MIN	TYP	MAX	UNITS	Notes
f(TCK_D)	TCK frequency (debug)			TBC	MHz	
f(TCK_B)	TCK frequency (boundary scan)			TBC	MHz	
T(SETUP)	TDO to TCK setup time	TBC			ns	A
T(HOLD)	TDO to TCK hold time	TBC			ns	A
T(DELAY)	TCK to output delay			TBC	ns	B

A Timing applies to TMS and TDI inputs.

B Timing applies to TDO output from negative edge of TCK.

All JTAG operations are synchronous to TCK.

19 Package Information



NOTE:

1. ALL DIMENSIONS ARE IN MILLIMETERS.
2. "e" REPRESENTS THE BASIC SOLDER BALL GRID PITCH.
3. "M" REPRESENTS THE MAXIMUM SOLDER BALL MATRIX SIZE.
4. DEMENSIONS "b" IS MEASURED AT THE MAXIMUM SOLDER BALL DIAMETER PARALLEL TO PRIMARY DATUM -C- .
5. PRIMARY DATUM -C- AND SEATING PLANE ARE DESIGNED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.
6. DIMENSIONING AND TOLERANCING PER ASME Y14.5M–1994
7. A1 CORNER MUST BE IDENTIFIED BY INK OR LASER MARK.
8. PACKAGE DIMENSIONS CONFORM TO JEDEC REGISTRATION MO–275.

SYMBOL	MIN.	NOM.	MAX.
A	1.16	1.26	1.36
A1	0.25	0.30	0.35
A2	0.91	0.96	1.01
D	15.90	16.00	16.10
E	15.90	16.00	16.10
I		0.80 REF.	
J		0.80 REF.	
M		19 X 19<DEPOPULATED>	
aaa			0.15
ccc			0.20
ddd			0.10
eee			0.15
fff			0.08
b	0.35	0.40	0.45
e		0.80 BSC.	
c		0.26 REF.	

0x15: Debug interrupt type

Bits	Perm	Init	Description
31:18	RO	-	Reserved
17:16	DRW		If the debug interrupt was caused by a hardware breakpoint or hardware watchpoint, this field contains the number of the breakpoint or watchpoint. If multiple breakpoints or watchpoints trigger at once, the lowest number is taken.
15:8	DRW		If the debug interrupt was caused by a logical core, this field contains the number of that core. Otherwise this field is 0.
7:3	RO	-	Reserved
2:0	DRW	0	Indicates the cause of the debug interrupt 1: Host initiated a debug interrupt through JTAG 2: Program executed a DCALL instruction 3: Instruction breakpoint 4: Data watch point 5: Resource watch point

B.17 Debug interrupt data: 0x16

On a data watchpoint, this register contains the effective address of the memory operation that triggered the debugger. On a resource watchpoint, it countains the resource identifier.

0x16: Debug interrupt data

Bits	Perm	Init	Description
31:0	DRW		Value.

B.18 Debug core control: 0x18

This register enables the debugger to temporarily disable logical cores. When returning from the debug interrupts, the cores set in this register will not execute. This enables single stepping to be implemented.

0x18: Debug core control

Bits	Perm	Init	Description
31:8	RO	-	Reserved
7:0	DRW		1-hot vector defining which logical cores are stopped when not in debug mode. Every bit which is set prevents the respective logical core from running.

B.19 Debug scratch: 0x20 .. 0x27

A set of registers used by the debug ROM to communicate with an external debugger, for example over JTAG. This is the same set of registers as the Debug Scratch registers in the xCORE tile configuration.

0x20 .. 0x27: Debug scratch

Bits	Perm	Init	Description
31:0	DRW		Value.

B.20 Instruction breakpoint address: 0x30 .. 0x33

This register contains the address of the instruction breakpoint. If the PC matches this address, then a debug interrupt will be taken. There are four instruction breakpoints that are controlled individually.

0x30 .. 0x33: Instruction breakpoint address

Bits	Perm	Init	Description
31:0	DRW		Value.

B.21 Instruction breakpoint control: 0x40 .. 0x43

This register controls which logical cores may take an instruction breakpoint, and under which condition.

0x40 .. 0x43: Instruction breakpoint control

Bits	Perm	Init	Description
31:24	RO	-	Reserved
23:16	DRW	0	A bit for each logical core in the tile allowing the breakpoint to be enabled individually for each logical core.
15:2	RO	-	Reserved
1	DRW	0	Set to 1 to cause an instruction breakpoint if the PC is not equal to the breakpoint address. By default, the breakpoint is triggered when the PC is equal to the breakpoint address.
0	DRW	0	When 1 the instruction breakpoint is enabled.

B.22 Data watchpoint address 1: 0x50 .. 0x53

This set of registers contains the first address for the four data watchpoints.

0x50 .. 0x53: Data watchpoint address 1

Bits	Perm	Init	Description
31:0	DRW		Value.

B.23 Data watchpoint address 2: 0x60 .. 0x63

This set of registers contains the second address for the four data watchpoints.

0x60 .. 0x63: Data watchpoint address 2

Bits	Perm	Init	Description
31:0	DRW		Value.

B.24 Data breakpoint control register: 0x70 .. 0x73

This set of registers controls each of the four data watchpoints.

0x70 .. 0x73: Data breakpoint control register

Bits	Perm	Init	Description
31:24	RO	-	Reserved
23:16	DRW	0	A bit for each logical core in the tile allowing the breakpoint to be enabled individually for each logical core.
15:3	RO	-	Reserved
2	DRW	0	Set to 1 to enable breakpoints to be triggered on loads. Breakpoints always trigger on stores.
1	DRW	0	By default, data watchpoints trigger if memory in the range [Address1..Address2] is accessed (the range is inclusive of Address1 and Address2). If set to 1, data watchpoints trigger if memory outside the range (Address2..Address1) is accessed (the range is exclusive of Address2 and Address1).
0	DRW	0	When 1 the instruction breakpoint is enabled.

B.25 Resources breakpoint mask: 0x80 .. 0x83

This set of registers contains the mask for the four resource watchpoints.

D Digital Node Configuration

The digital node control registers can be accessed using configuration reads and writes (use `write_node_config_reg(device, ...)` and `read_node_config_reg(device, ...)` for reads and writes).

Number	Perm	Description
0x00	RO	Device identification
0x01	RO	System switch description
0x04	RW	Switch configuration
0x05	RW	Switch node identifier
0x06	RW	PLL settings
0x07	RW	System switch clock divider
0x08	RW	Reference clock
0x0C	RW	Directions 0-7
0x0D	RW	Directions 8-15
0x10	RW	DEBUG_N configuration
0x1F	RO	Debug source
0x20 .. 0x27	RW	Link status, direction, and network
0x40 .. 0x43	RW	PLink status and network
0x80 .. 0x87	RW	Link configuration and initialization
0xA0 .. 0xA7	RW	Static link configuration

Figure 46: Summary

D.1 Device identification: 0x00

This register contains version and revision identifiers and the mode-pins as sampled at boot-time.

Bits	Perm	Init	Description
31:24	RO	0x00	Chip identifier.
23:16	RO		Sampled values of pins MODE0, MODE1, ... on reset.
15:8	RO		SSwitch revision.
7:0	RO		SSwitch version.

0x00: Device identification

D.2 System switch description: 0x01

This register specifies the number of processors and links that are connected to this switch.

0x10: UIFM on-the-go control

Bits	Perm	Init	Description
31:8	RO	-	Reserved
7	RW	0	Set to 1 to switch UIFM to EXTVBUSIND mode.
6	RW	0	Set to 1 to switch UIFM to DRVVBUSEXT mode.
5	RO	-	Reserved
4	RW	0	Set to 1 to switch UIFM to UTMI+ CHRGVBUS mode.
3	RW	0	Set to 1 to switch UIFM to UTMI+ DISCHRGVBUS mode.
2	RW	0	Set to 1 to switch UIFM to UTMI+ DMPULLDOWN mode.
1	RW	0	Set to 1 to switch UIFM to UTMI+ DPPULLDOWN mode.
0	RW	0	Set to 1 to switch UIFM to IDPULLUP mode.

F.6 UIFM on-the-go flags: 0x14

Status flags used for on-the-go negotiation

0x14: UIFM on-the-go flags

Bits	Perm	Init	Description
31:6	RO	-	Reserved
5	RO	0	Value of UTMI+ Bvalid flag.
4	RO	0	Value of UTMI+ IDGND flag.
3	RO	0	Value of UTMI+ HOSTDIS flag.
2	RO	0	Value of UTMI+ VBUSVLD flag.
1	RO	0	Value of UTMI+ SESSVLD flag.
0	RO	0	Value of UTMI+ SESSEND flag.

0x24: Power sequence status

Bits	Perm	Init	Description
31:30	RO	-	Reserved
29	RO	0	1 if VOUT6 was enabled in the previous state.
28	RO	0	1 if LDO5 was enabled in the previous state.
27:26	RO	-	Reserved
25	RO	1	1 if DCDC2 was enabled in the previous state.
24	RO	0	1 if DCDC1 was enabled in the previous state.
23:19	RO	-	Reserved
18:16	RO		Current state of the power sequence state machine 0: Reset 1: Asleep 2: Waking 1 3: Waking 2 4: Awake Wait 5: Awake 6: Sleeping 1 7: Sleeping 2
15	RO	-	Reserved
14	RO	0	Set to 1 to disable clock to the xCORE Tile.
13:10	RO	-	Reserved
9	RO	0	Sets modulation used by DCDC2: 0: PWM modulation (max 475 mA) 1: PFM modulation (max 50 mA)
8	RO	0	Sets modulation used by DCDC1: 0: PWM modulation (max 700 mA) 1: PFM modulation (max 50 mA)
7:6	RO	-	Reserved
5	RO	0	Set to 1 to enable VOUT6 (IO supply).
4	RO	0	Set to 1 to enable LDO5 (core PLL supply).
3:2	RO	-	Reserved
1	RO	0	Set to 1 to enable DCDC2 (analogue supply).
0	RO	0	Set to 1 to enable DCDC1 (core supply).

K.11 DCDC control: 0x2C

This register controls the two DC-DC converters.